What is claimed is:

1	1. A method of detecting a defect in a scan chain, the method comprising:
2	applying a plurality of pattern sets to a scan chain coupled to an array
3	built-in self-test (ABIST) circuit;
4	collecting, from the scan chain, scan out data generated as a result of the
5	application of the plurality of pattern sets to the scan chain; and
6	using the collected scan out data to identify a defective latch in the scan
7	chain.
1	2. The method of claim 1, further comprising:
2	sensitizing at least one alternate path within which the scan chain is
3	disposed; and
4	applying a second plurality of pattern sets to the scan chain while the
5	alternate path is sensitized.
1	3. The method of claim 1, wherein using the collected scan out data to identify
2	the defective latch includes identifying a location of the defective latch in the scan chain
1	4. The method of claim 1, further comprising performing at least one of a scan
2	test and a flush test prior to applying the plurality of pattern sets to the scan chain.
1	5. The method of claim 1, wherein applying the plurality of pattern sets includes
2	laterally inserting each pattern set into the scan chain using the ABIST circuit.
1	6. The method of claim 1, wherein collecting the scan out data includes serially
2	stepping the scan out data through the scan chain to an output thereof.
1	7. The method of claim 1, further comprising reconfiguring the scan chain prior
2	to collecting the scan out data.

8. An apparatus, comprising: 1 2 a memory; and 3 program code resident in the memory and configured to detect a defect in a scan chain disposed in an integrated circuit device by collecting, from the scan 4 chain, scan out data generated as a result of an application of a plurality of pattern 5 sets to the scan chain by an array built-in self-test (ABIST) circuit disposed in the 6 7 integrated circuit device, and using the collected scan out data to identify a defective latch in the scan chain. 8 1 9. The apparatus of claim 8, wherein the program code is further configured to sensitize at least one alternate path within which the scan chain is disposed, and apply a 2 3 second plurality of pattern sets to the scan chain while the alternate path is sensitized. 10. The apparatus of claim 8, wherein the program code is configured to use the 1 collected scan out data to identify the defective latch by identifying a location of the 2 3 defective latch in the scan chain. 11. The apparatus of claim 8, wherein the program code is further configured to 1 2 perform at least one of a scan test and a flush test prior to applying the plurality of pattern 3 sets to the scan chain. 1 12. The apparatus of claim 8, wherein the program code is configured to apply the plurality of pattern sets by laterally inserting each pattern set into the scan chain using 2 3 the ABIST circuit. 1 13. The apparatus of claim 8, wherein the program code is configured to collect 2 the scan out data by serially stepping the scan out data through the scan chain to an output 3 thereof.

1	14. The apparatus of claim 8, wherein the program code is further configured to
2	reconfigure the scan chain prior to collecting the scan out data.
1	15. The apparatus of claim 8, wherein at least a portion of the program code is
2	resident in a test platform.
1	16. The apparatus of claim 15, wherein at least a second portion of the program
)	code is resident in computer coupled to the test platform

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1 17. A program product, comprising: 2 program code configured to detect a defect in a scan chain disposed in an 3 integrated circuit device by collecting, from the scan chain, scan out data 4 generated as a result of an application of a plurality of pattern sets to the scan chain by an array built-in self-test (ABIST) circuit disposed in the integrated 5 6 circuit device, and using the collected scan out data to identify a defective latch in the scan chain; and 7 8 a computer readable signal bearing medium bearing the program code. 18. The program product of claim 17, wherein the computer readable signal 1 2 bearing medium includes at least one of a transmission medium and a recordable 3 medium.